Status of the deformation measurement setup & software

Basic principle



- surface under test reflects a grid of dots or LEDs, observed by a CCD
- tilt of surface elements (deformations) lead to a displacement of the dots on the CCD
- full 3D "sampled" surface reconstruction possible
 - relative to a reference shape/image (typically at room temperature)
 - » accuracy ~10 µm can be reached
 - > only "intrinsic" deformation global offsets or tilts cannot be reconstructed

Teststand mock-up



Lots of cardboard & duct tape

Dot grid (34 x 20 cm) 1 mm bores, 1 cm spacing



Calibration surface



Calibration surface



Reconstruction: reference image

Reference image:

 micrometer screw gently touches sheet (slight bias)

 for thermal defo measurements, reference would typically be at room temperature

					-						
nline Cooling	Offline	Advanced									
			Current raw image		Measurement ID						
				Area							
				no. 🗢	Edit Default	QUIT					
				New	Image info						
				Delete	Raw image size: 1729 x 1156 pixe Fetched: 20.12.11 10:25:08	21					
				Display — O Points	Type: from disk []						
				Areas							
				 Splines Coords 							
				Refresh	Schedule						
· · ·				Camera	ACTION VALUE	#					
• • •				File	2 3						
				Manual Manual	4 5						
				Ref	6 7						
· · ·				Defo	8						
• • •				Temp	10						
• • •					12						
					14						
X ↑					Verify Clear Load	Save					
$\longrightarrow Y$					START PAUSE/RES	STOP					

Reconstruction: reference image



Reconstruction: deformation image

Deformation image:

- micrometer screw
 500 µm upwards
- some postprocessing necessary due to very low contrast and bad ambient light conditions (few points manually enhanced)

"bump" from the pressure point

Online		<u>.</u>												
							Area no. ↓ New Delete Display ● Points ● Areas □ Indices ● Splines ● Coords Refresh Camera	Measurement ID defomeasurement-201211-102420 Edit Default QUIT Image info Raw image size: 1729 x 1156 pixel Fetched: 20.12.11 10:40:10 Type: from disk [test/test3/defo50_crp.jpg]						
								File Manual Ref Defo Temp	1 2 3 4 5 6 6 7 8 9 9 10 11 12 13 14		test/ test/	test3/ref_ test3/ref_ test3/defa	_cr.jpg p50_crp.j	save

Reconstruction: surface

Result yields ~320 µm deformation amplitude

- reconstruction parameters (setup geometry) not yet properly adjusted
- metal sheet too stiff and not uniform (kinks)
- postprocessing might have introduced a bias ("bump" might be more protruding)
- parts of the surface obstructed by reels





\rightarrow systematic measurements at various amplitudes

Software developments

Already functional:

- remote operation of camera
- image analysis (histograms, etc.)
- file & reconstruction results output
- restrict reconstruction to areas
- programmable schedule (automatic measurement series, temperature cycles, etc.)

Upcoming:

- chiller remote control
- partly
- temperature probes
- done
- standalone result "viewer"
- camera whitebalance
- multiple simultaneous areas processing
- whatever else is needed ...





Final setup

- for large scale application up to ~ 80 x 80 cm (ATLAS petals)
- dark environment, low ambient light through LED backlight illumination
- some scaffolding parts already delivered
- need to duplicate temperature probe readout
- time scale ~ 2 months





more slides

surface reconstruction: point finding





- scan along x,y row-wise and compute grayscale ADC values
- stop at pixel > threshold T1 (step1 seed)
 - evaluate group of pixels in vicinity
 - if average > threshold **T2** (step2 seed)
 - accept point
 - determine point position by center-of gravity of all pixels around seed2 with grayscale ADC > threshold T3
 - average red/cyan ratio of pixels to determine if the point is "red"



surface reconstruction: point indexing

Must consider that points might be missing:

- gaps in multi-component surfaces
- points not properly reflected (diffraction, surface quality, ...)

Indexing assigns position indices (0..N, 0..M) to the reconstructed points:

- 1:1 matching of reflected points to the grid
- red point in the middle is used as reference (0,0)
- average spacing along x and y is determined to estimate the positions of the next point(s)



Indices are used to match points in reference and "current" image

Requires proper tuning of reconstruction & setup parameters (size of search window, distance of dots in grid, etc.)

surface reconstruction: calculating the surface slope



surface reconstruction: spline fitting

Indexed points are grouped in "rows" (along x) and "columns" (along y) \rightarrow fit a quadratic spline to each group

$$h(x) = A \cdot x^2 + B \cdot x + C$$

h := surface height (deformation amplitude)





For all splines along a "row" or "column" :

 $h_j(x_{j+1}) = h_{j+1}(x_{j+1})$ for j = 1..N - 1 continuity at the intersections

$$\frac{\delta h_j}{\delta x}(x_{j+1}) = \frac{\delta h_{j+1}}{\delta x}(x_{j+1}) = h_{j+1} \text{ for } j = 1..N - 1 \qquad \text{continuity of } 1^{\text{st}} \text{ derivative}$$

 $\frac{\delta h_1}{\delta x}(x_1) = s_1, h_1 = 0$

freedom of choice for global height (parameter C) which cannot be reconstructed since we have changes in slope ΔS only

 \rightarrow equation system can be solved to obtain surface profile along spline

surface reconstruction: spline cross-mounting

Splines are "cross-mounted" on each other:

- take 1st spline along x and adjust the height of all perpendicular y-splines at the shared point ("mount" them on the x-spline)
- take 2nd spline along x ...

...

- The average of all adjustments determines the global height of a spline \rightarrow smooth surface

Finally, correct for global surface height offset (lowest point set to 0) and tilt (rotate surface such that average normal is perpendicular to x-y-plane, TODO)

simulation examples: a sine "wave" along y

